

13 μ A/ch, Rail-to-Rail Output Dual CMOS Operational Amplifier

■ GENERAL DESCRIPTION

The NJU7027 is a low power, dual CMOS operational amplifier. It is tolerant to RF noise. The NJU7027 can operate from a single-supply voltage of +1.8V to +5.5V. In addition, this amplifier features Rail-to-Rail output and low input bias current (1pA). Because of these features, the NJU7027 is ideal for low side current sense amplifier. The very low supply current of the NJU7027 (13 μ A/ch) makes it suitable for battery-operated application.

■ PACKAGE OUTLINE



NJU7027RB1

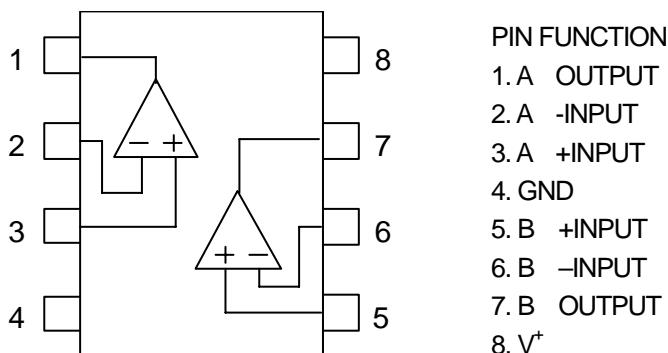
■ FEATURES

- Low Supply Current 13 μ A/ch typ. (at V_{DD}= 5V), 12 μ A/ch typ. (at V_{DD}= 3V)
11 μ A/ch typ. (at V_{DD}= 1.8V)
- Low Operating Voltage V_{OPR}= 1.8V to 5.5V
- Rail-to-Rail Output V_{OH}=4.9V min./ V_{OL}=0.1V max. (at V_{DD}= 5V, R_L=100k Ω)
V_{OH}=4.8V min./ V_{OL}=0.2V max. (at V_{DD}= 5V, I_O=1mA)
- Package TVS8P
- Enhanced RF Noise Immunity
- CMOS Process

■ APPLICATION

- Battery-operated application
- Battery monitor
- Current sensor
- Photodiode amplification

■ PIN CONFIGURATION (Top View)



NJU7027

■ ABSOLUTE MAXIMUM RATINGS (Ta=25°C, unless otherwise noted.)

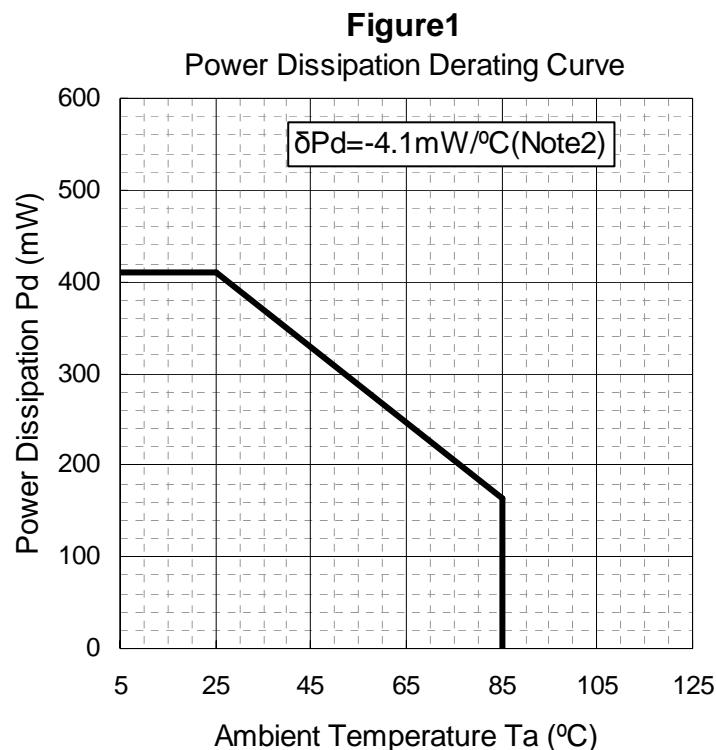
PARAMETER	SYMBOL	RATINGS	UNIT
Supply Voltage	V _{DD}	+7	V
Input Common Mode Voltage	V _{ICM}	V _{SS} -0.3 to V _{DD} +0.3	V
Differential Input Voltage	V _{ID}	±7 (Note1)	V
Power Dissipation	P _D	410 (Note2)	mW
Operating Temperature Range	T _{opr}	-40 to +85	°C
Storage Temperature Range	T _{stg}	-55 to +125	°C

(Note1) For supply voltage less than +7V, the absolute maximum rating is equal to the supply voltage.

(Note2) EIA/JEDEC STANDARD Test board (76.2 x 114.3 x 1.6mm, 2layers, FR-4) mounting.

(Note3) Do not exceed "Power dissipation: P_D" in which power dissipation in IC is shown by the absolute maximum rating.

See Figure "Power Dissipation Curve" when ambient temperature is over 25°C.



■ RECOMMENDED OPERATING CONDITION(Ta=25°C)

PARAMETER	SYMBOL	RATING	UNIT
Supply Voltage	V _{DD}	1.8 to 5.5	V

■ ELECTRICAL CHARACTERISTICS

DC CHARACTER ($V_{DD}=5V$, $V_{SS}=0V$, $T_a=25^{\circ}C$, unless otherwise noted.)

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Supply Current	I_{DD}	No Signal	-	26	40	μA
Input Offset Voltage	V_{IO}	$V_{IC}=0V$, $R_S=50\Omega$	-	0.9	4	mV
Input Offset Voltage drift	$\Delta V_{IO}/\Delta T$		-	1.5	-	$\mu V/{\circ}C$
Input Bias Current	I_B		-	1	-	pA
Input Offset Current	I_{IO}		-	1	-	pA
Open loop gain	A_V	$V_o=0.5V$ to $4.5V$, $R_L=100k\Omega$ to $2.5V$	70	90	-	dB
Common Mode Rejection Ratio	CMR	$V_{ICM}=0V$ to $4.1V$	65	80	-	dB
Supply Voltage Rejection Ratio	SVR	$V_{DD}=1.8V$ to $5.5V$	70	90	-	dB
Maximum Output Voltage 1	V_{OH1}	$R_L=100k\Omega$ to $2.5V$	4.9	4.95	-	V
	V_{OL1}	$R_L=100k\Omega$ to $2.5V$	-	0.05	0.1	V
Maximum Output Voltage 2	V_{OH2}	$R_L=100k\Omega$ to $0V$	4.9	4.95	-	V
	V_{OL2}	$R_L=100k\Omega$ to $0V$	-	0.02	0.05	V
Maximum Output Voltage 3	V_{OH3}	$I_{source}=1mA$	4.8	4.85	-	V
	V_{OL3}	$I_{sink}=1mA$	-	0.15	0.2	V
Common Mode Input Voltage Range	V_{ICM}	CMR $\geq 65dB$	0	-	4.1	V

AC CHARACTER ($V_{DD}=5V$, $V_{SS}=0V$, $T_a=25^{\circ}C$, unless otherwise noted.)

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gain Bandwidth Product	GBW	$R_L=100k\Omega$ to $2.5V$, $C_L=20pF$, $f=10kHz$	-	160	-	kHz
Phase Margin	ϕ_M	$R_L=100k\Omega$ to $2.5V$, $C_L=20pF$	-	80	-	deg
Gain Margin	G_M	$R_L=100k\Omega$ to $2.5V$, $C_L=20pF$	-	15	-	dB
Equivalent Input Noise Voltage	e_n	$f=1kHz$	-	50	-	nV/ \sqrt{Hz}
Channel Separation	CS	$f=1kHz$	-	120	-	dB
Slew Rate	SR	$G_V=0dB$, $R_L=100k\Omega$ to $2.5V$, $C_L=20pF$, $V_{in}=3Vpp$ (1V to 4V) (Note4) (Note5)	-	0.05	-	V/us
Power Bandwidth	PBW	$G_V=6dB$, $R_F=50k\Omega$, $R_G=50k\Omega$, $C_L=20pF$, $V_{in}=2.5Vpp$ (1.25V to 3.75V), $V_o\geq 4.8Vpp$ (Note6)	-	5	-	kHz
Total Harmonic Distortion	THD	$G_V=6dB$, $R_F=50k\Omega$, $R_G=50k\Omega$, $C_L=20pF$, $V_o=4Vpp$, $f=100Hz$ (Note6)	-	0.01	-	%

(Note4) Slew rate is defined by the lower value of the rise or fall.

(Note5) See figure2-1 for test circuit.

(Note6) See figure2-3 for test circuit.

NJU7027

ELECTRICAL CHARACTERISTICS

DC CHARACTER ($V_{DD}=3V$, $V_{SS}=0V$, $T_a=25^{\circ}C$, unless otherwise noted.)

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Supply Current	I_{DD}	No Signal	-	24	36	μA
Input Offset Voltage	V_{IO}	$V_{IC}=0V$, $R_S=50\Omega$	-	0.9	4	mV
Input Offset Voltage drift	$\Delta V_{IO}/\Delta T$		-	1.5	-	$\mu V/{\circ}C$
Input Bias Current	I_B		-	1	-	pA
Input Offset Current	I_O		-	1	-	pA
Open loop gain	A_V	$V_o=0.5V$ to $2.5V$, $R_L=100k\Omega$ to $1.5V$	70	90	-	dB
Common Mode Rejection Ratio	CMR	$V_{ICM}=0V$ to $2.1V$	65	80	-	dB
Supply Voltage Rejection Ratio	SVR	$V_{DD}=1.8V$ to $5.5V$	70	90	-	dB
Maximum Output Voltage 1	V_{OH1}	$R_L=100k\Omega$ to $1.5V$	2.9	2.95	-	V
	V_{OL1}	$R_L=100k\Omega$ to $1.5V$	-	0.05	0.1	V
Maximum Output Voltage 2	V_{OH2}	$R_L=100k\Omega$ to $0V$	2.9	2.95	-	V
	V_{OL2}	$R_L=100k\Omega$ to $0V$	-	0.02	0.05	V
Maximum Output Voltage 3	V_{OH3}	$I_{source}=1mA$	2.8	2.85	-	V
	V_{OL3}	$I_{sink}=1mA$	-	0.15	0.2	V
Common Mode Input Voltage Range	V_{ICM}	CMR $\geq 65dB$	0	-	2.1	V

AC CHARACTER ($V_{DD}=3V$, $V_{SS}=0V$, $T_a=25^{\circ}C$, unless otherwise noted.)

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gain Bandwidth Product	GBW	$R_L=100k\Omega$ to $1.5V$, $C_L=20pF$, $f=10kHz$	-	150	-	kHz
Phase Margin	ϕ_M	$R_L=100k\Omega$ to $1.5V$, $C_L=20pF$	-	80	-	deg
Gain Margin	G_M	$R_L=100k\Omega$ to $1.5V$, $C_L=20pF$	-	15	-	dB
Equivalent Input Noise Voltage	e_n	$f=1kHz$	-	50	-	nV/ \sqrt{Hz}
Channel Separation	CS	$f=1kHz$	-	115	-	dB
Slew Rate	SR	$G_v=0dB$, $R_L=100k\Omega$ to $1.5V$, $C_L=20pF$, $V_{in}=1Vpp$ (1V to 2V) (Note4) (Note5)	-	0.05	-	V/us
Power Bandwidth	PBW	$G_v=6dB$, $R_F=50k\Omega$, $R_G=50k\Omega$, $C_L=20pF$, $V_{in}=1.5Vpp$ (0.75V to 2.25V), $V_o\geq 2.8Vpp$ (Note6)	-	8	-	kHz
Total Harmonic Distortion	THD	$G_v=6dB$, $R_F=50k\Omega$, $R_G=50k\Omega$, $C_L=20pF$, $V_o=2Vpp$, $f=100Hz$ (Note6)	-	0.01	-	%

(Note4) Slew rate is defined by the lower value of the rise or fall.

(Note5) See figure2-1 for test circuit.

(Note6) See figure2-3 for test circuit.

■ ELECTRICAL CHARACTERISTICS

DC CHARACTER ($V_{DD}=1.8V$, $V_{SS}=0V$, $T_a=25^{\circ}C$, unless otherwise noted.)

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Supply Current	I_{DD}	No Signal	-	22	34	μA
Input Offset Voltage	V_{IO}	$V_{IC}=0V$, $R_S=50\Omega$	-	0.9	4	mV
Input Offset Voltage drift	$\Delta V_{IO}/\Delta T$		-	1.5	-	$\mu V/{\circ}C$
Input Bias Current	I_B		-	1	-	pA
Input Offset Current	I_O		-	1	-	pA
Open loop gain	A_V	$V_o=0.5V$ to $2.5V$, $R_L=100k\Omega$ to $0.9V$	70	90	-	dB
Common Mode Rejection Ratio	CMR	$V_{ICM}=0V$ to $0.9V$	65	80	-	dB
Supply Voltage Rejection Ratio	SVR	$V_{DD}=1.8V$ to $5.5V$	70	90	-	dB
Maximum Output Voltage 1	V_{OH1}	$R_L=100k\Omega$ to $0.9V$	1.7	1.75	-	V
	V_{OL1}	$R_L=100k\Omega$ to $0.9V$	-	0.05	0.1	V
Maximum Output Voltage 2	V_{OH2}	$R_L=100k\Omega$ to $0V$	1.7	1.75	-	V
	V_{OL2}	$R_L=100k\Omega$ to $0V$	-	0.02	0.05	V
Maximum Output Voltage 3	V_{OH3}	$I_{source}=0.5mA$	1.5	1.55	-	V
	V_{OL3}	$I_{sink}=0.5mA$	-	0.25	0.3	V
Common Mode Input Voltage Range	V_{ICM}	CMR \geq 65dB	0	-	0.9	V

AC CHARACTER ($V_{DD}=1.8V$, $V_{SS}=0V$, $T_a=25^{\circ}C$, unless otherwise noted.)

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gain Bandwidth Product	GBW	$R_L=100k\Omega$ to $0.9V$, $C_L=20pF$, $f=10kHz$	-	140	-	kHz
Phase Margin	ϕ_M	$R_L=100k\Omega$ to $0.9V$, $C_L=20pF$	-	80	-	deg
Gain Margin	G_M	$R_L=100k\Omega$ to $0.9V$, $C_L=20pF$	-	15	-	dB
Equivalent Input Noise Voltage	e_n	$f=1kHz$	-	50	-	nV/ \sqrt{Hz}
Channel Separation	CS	$f=1kHz$	-	110	-	dB
Slew Rate	SR	$G_V=0dB$, $R_L=100k\Omega$ to $1.5V$, $C_L=20pF$, $V_{in}=0.5Vpp$ (0.3V to 0.8V) (Note4) (Note7)	-	0.05	-	V/us
Power Bandwidth	PBW	$G_V=6dB$, $R_F=50k\Omega$, $R_G=50k\Omega$, $C_L=20pF$, $V_{in}=0.9Vpp$ (0V to 0.9V), $V_o\geq1.6Vpp$ (Note8)	-	14	-	kHz
Total Harmonic Distortion	THD	$G_V=6dB$, $R_F=50k\Omega$, $R_G=50k\Omega$, $C_L=20pF$, $V_o=1Vpp$, $f=100Hz$ (Note8)	-	0.01	-	%

(Note4) Slew rate is defined by the lower value of the rise or fall.

(Note7) See figure2-2 for test circuit.

(Note8) See figure2-4 for test circuit..

■ MEASUREMENT CIRCUITS

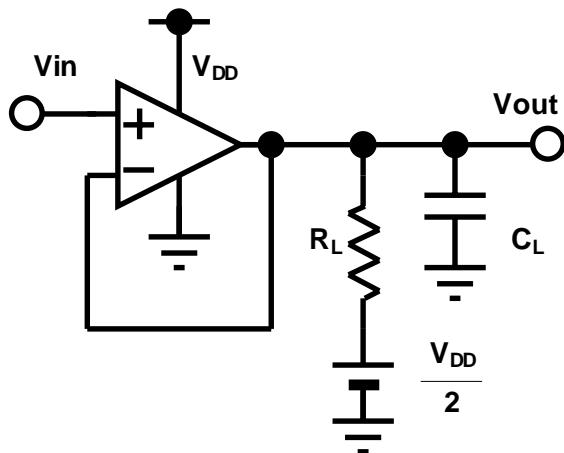


Figure 2-1:Measurement circuit 1

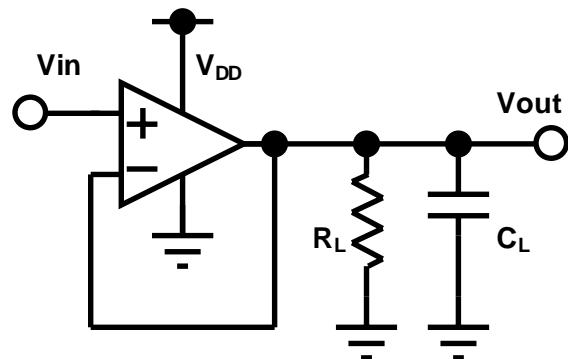


Figure 2-2:Measurement circuit 2

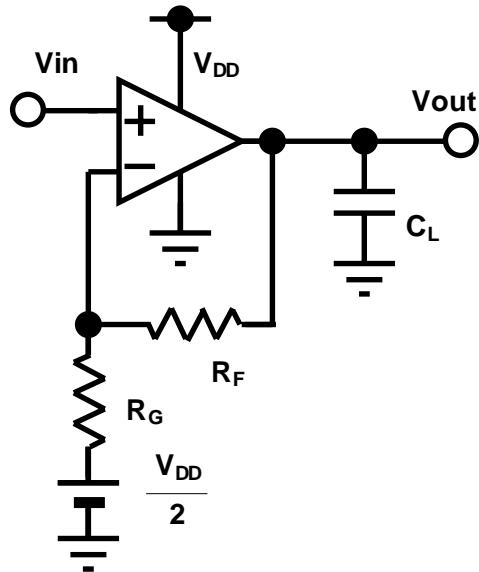


Figure 2-3:Measurement circuit 3

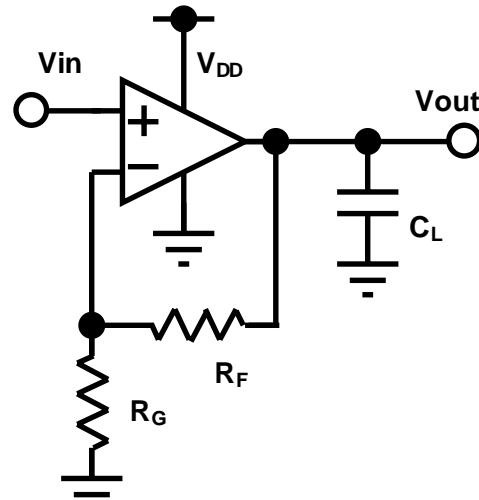
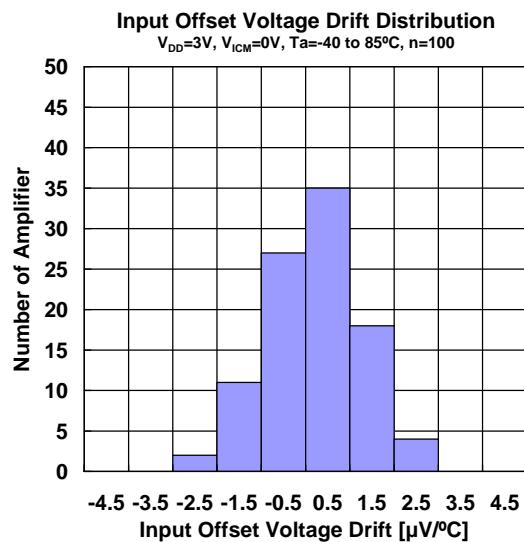
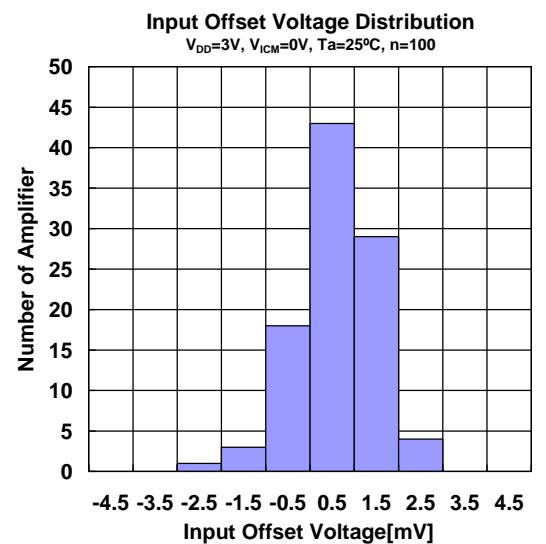
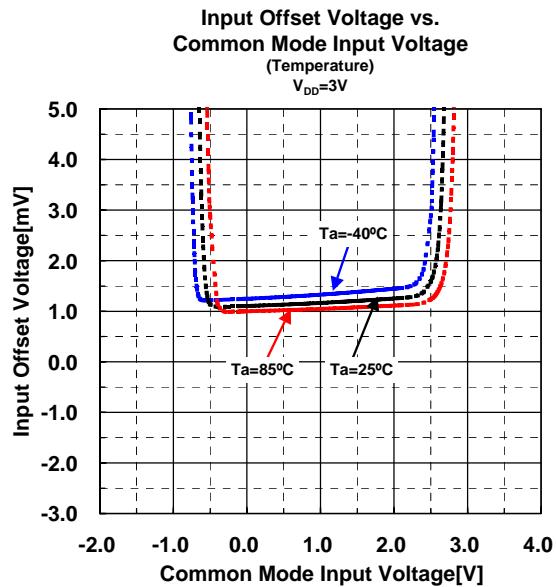
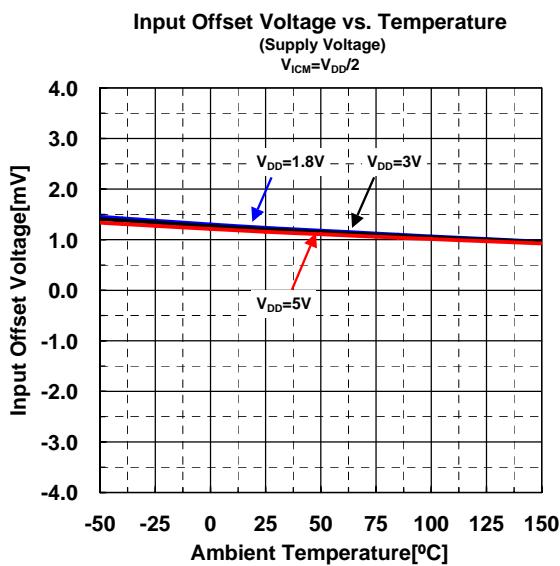
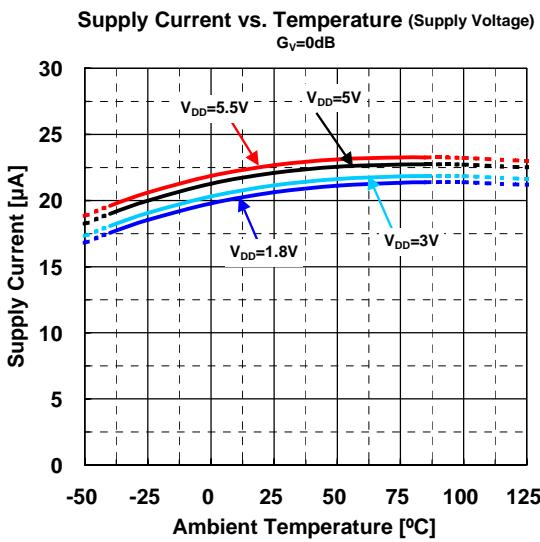
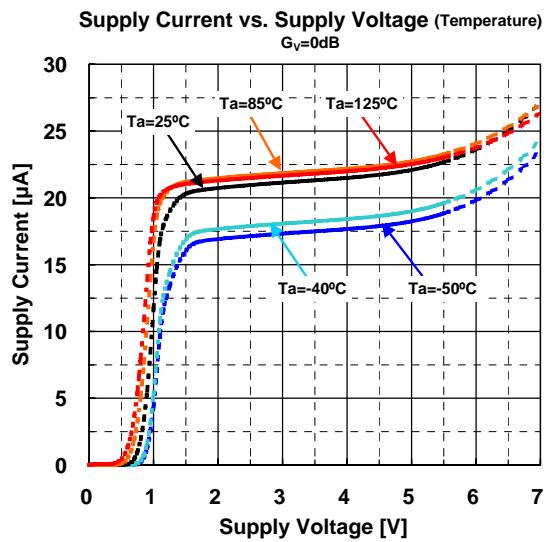
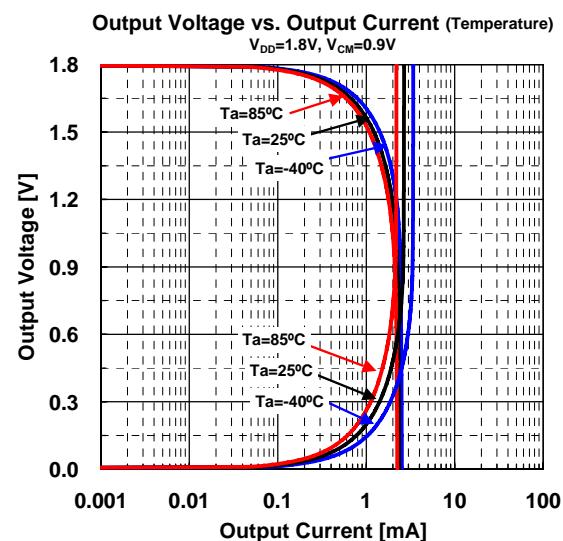
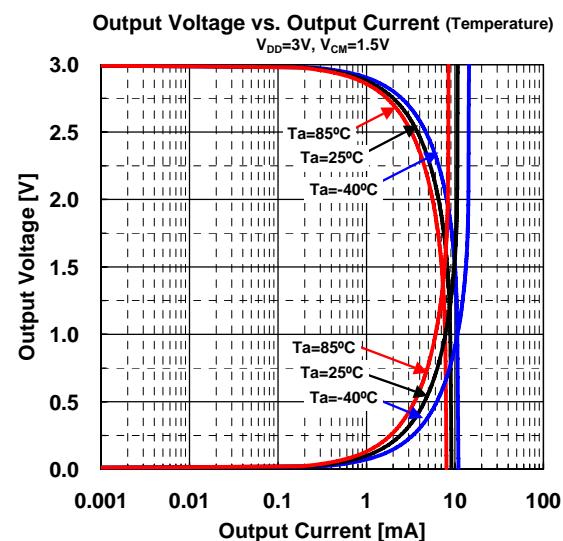
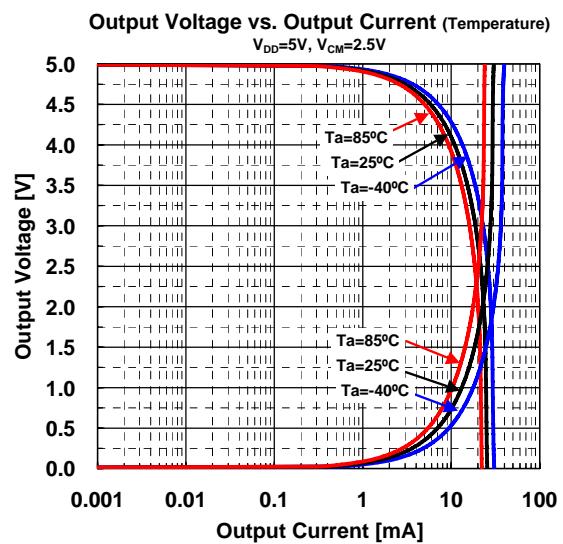
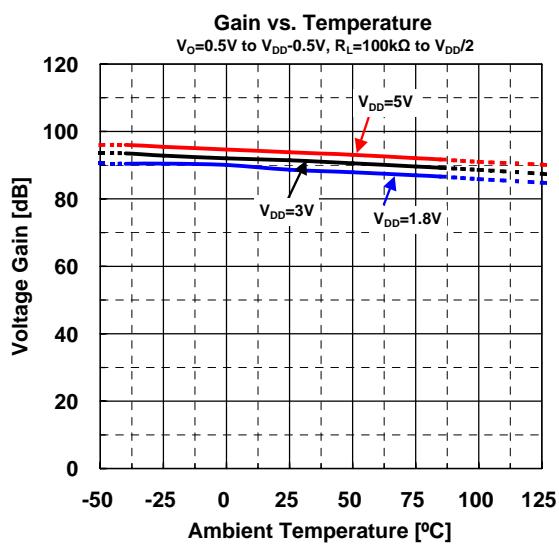
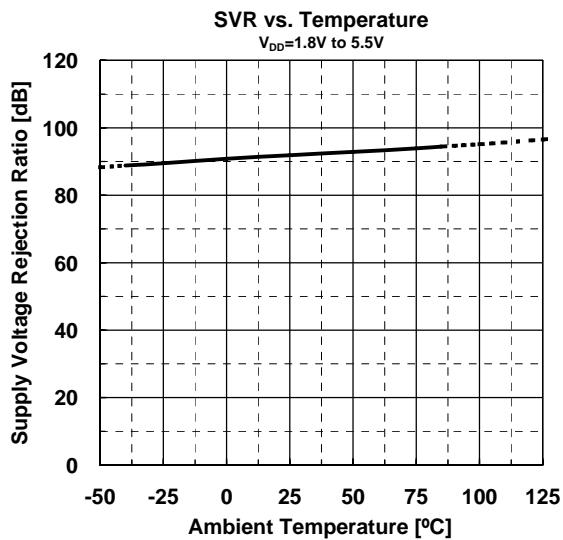
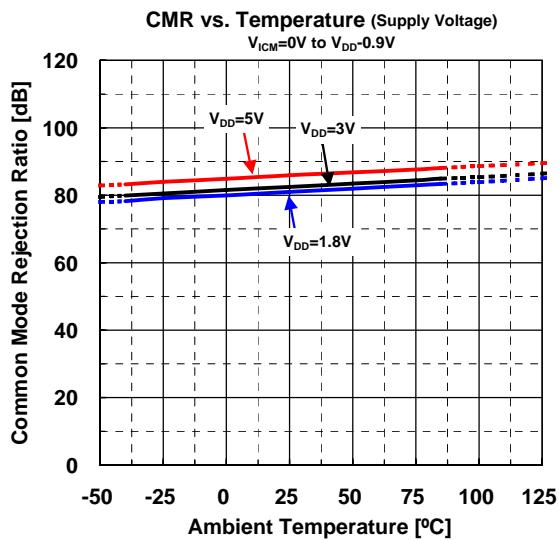


Figure 2-4:Measurement circuit 4

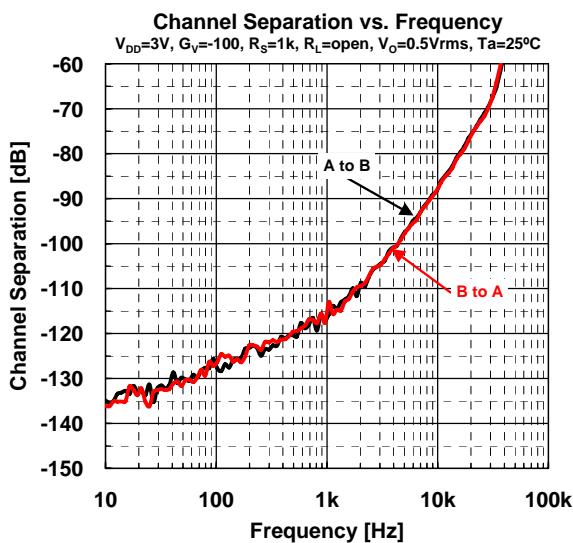
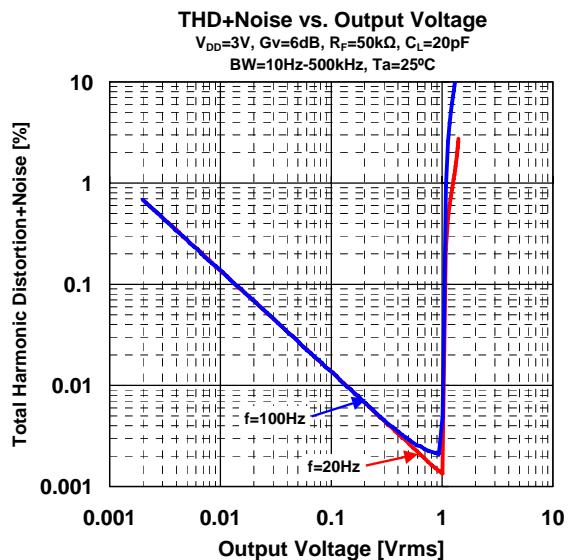
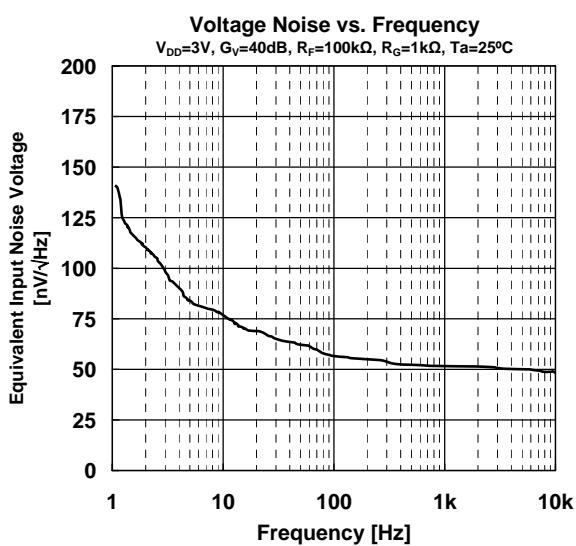
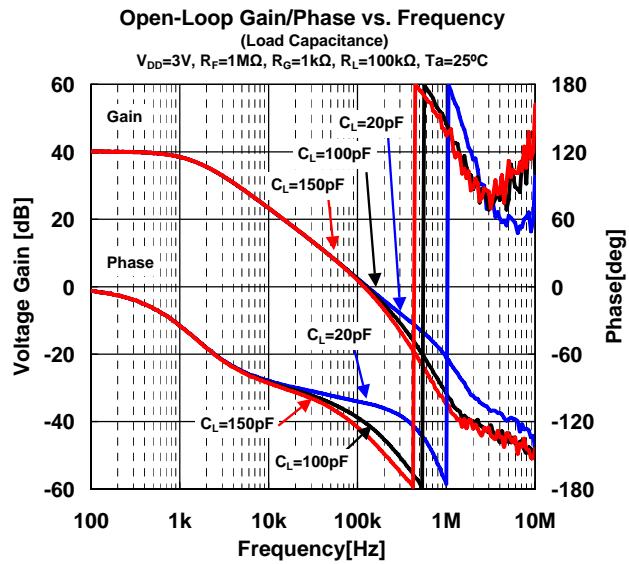
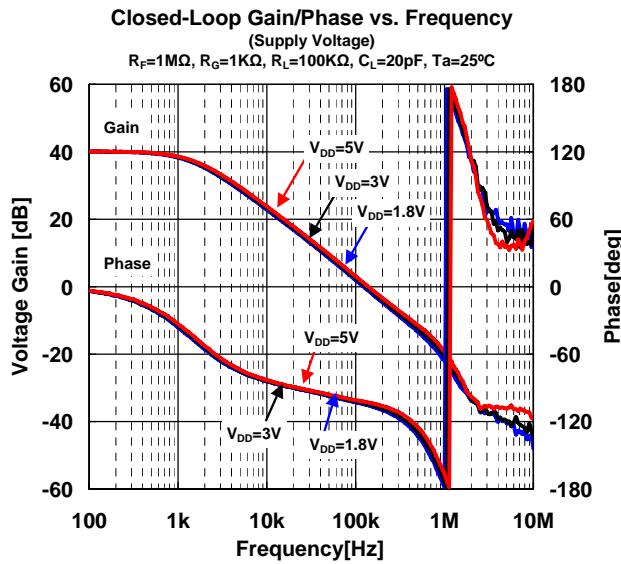
■ TYPICAL CHARACTERISTICS



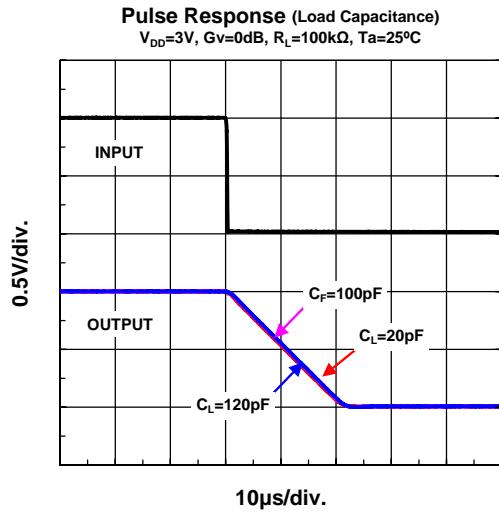
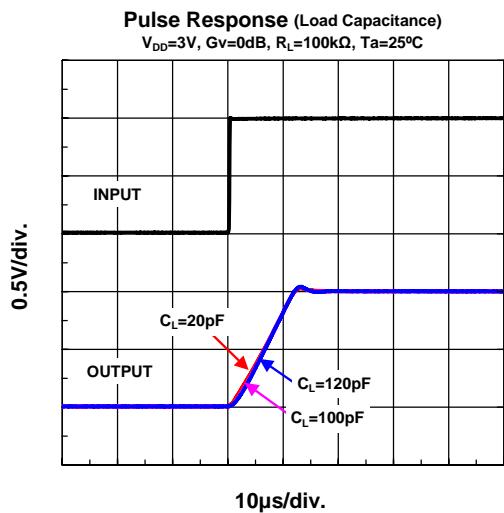
■ TYPICAL CHARACTERISTICS



■ TYPICAL CHARACTERISTICS



■ TYPICAL CHARACTERISTICS



■ MEMO

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